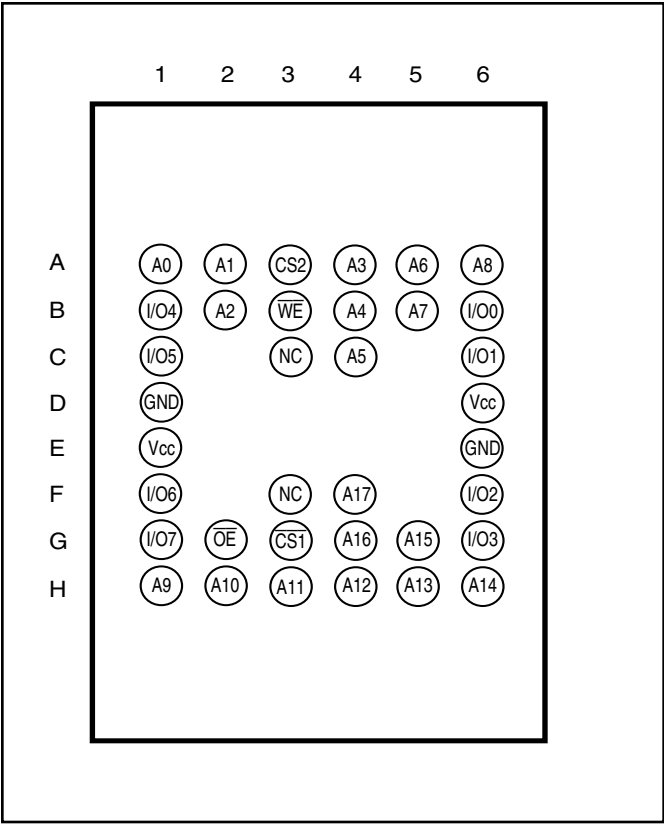


PIN DESCRIPTIONS

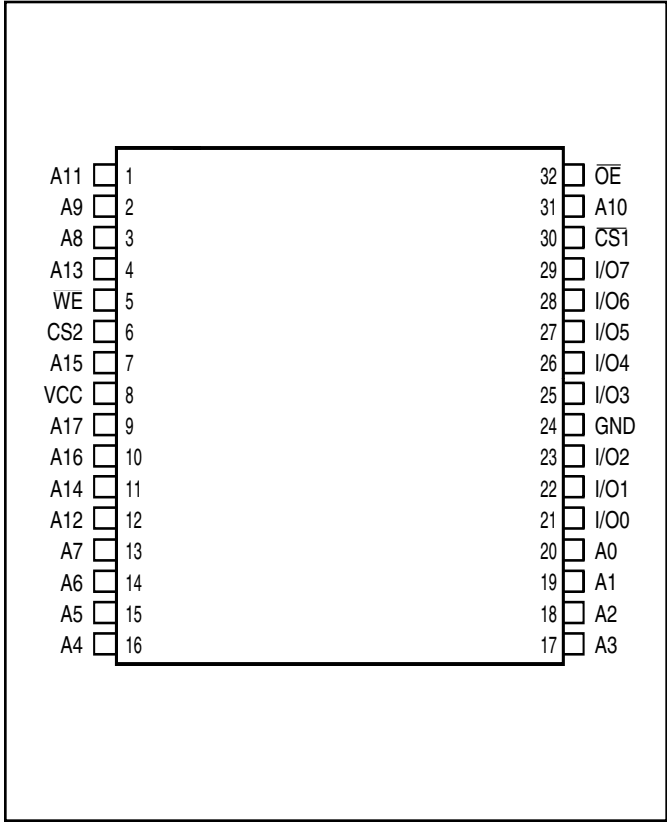
A0-A17	Address Inputs
$\overline{CS1}$	Chip Enable 1 Input
CS2	Chip Enable 2 Input
\overline{OE}	Output Enable Input
\overline{WE}	Write Enable Input
I/O0-I/O7	Input/Output
NC	No Connection
Vcc	Power
GND	Ground

PIN CONFIGURATION

36-pin mini BGA (B) (6mm x 8mm)



32-pin TSOP (TYPE I), sTSOP (TYPE I)



ABSOLUTE MAXIMUM RATINGS⁽¹⁾

Symbol	Parameter	Value	Unit
V _{TERM}	Terminal Voltage with Respect to GND	-0.2 to V _{CC} +0.3	V
T _{STG}	Storage Temperature	-65 to +150	°C
P _T	Power Dissipation	1.0	W

Note:

1. Stress greater than those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.

OPERATING RANGE (V_{CC})

Range	Ambient Temperature	IS62WV2568ALL	IS62WV2568BLL
Commercial	0°C to +70°C	1.65V - 2.2V	2.5V - 3.6V
Industrial	-40°C to +85°C	1.65V - 2.2V	2.5V - 3.6V

DC ELECTRICAL CHARACTERISTICS (Over Operating Range)

Symbol	Parameter	Test Conditions	V _{CC}	Min.	Max.	Unit
V _{OH}	Output HIGH Voltage	I _{OH} = -0.1 mA	1.65-2.2V	1.4	—	V
		I _{OH} = -1 mA	2.5-3.6V	2.2	—	V
V _{OL}	Output LOW Voltage	I _{OL} = 0.1 mA	1.65-2.2V	—	0.2	V
		I _{OL} = 2.1 mA	2.5-3.6V	—	0.4	V
V _{IH}	Input HIGH Voltage		1.65-2.2V	1.4	V _{CC} + 0.2	V
			2.5-3.6V	2.2	V _{CC} + 0.3	V
V _{IL} ⁽¹⁾	Input LOW Voltage		1.65-2.2V	-0.2	0.4	V
			2.5-3.6V	-0.2	0.6	V
I _{LI}	Input Leakage	GND ≤ V _{IN} ≤ V _{CC}		-1	1	μA
I _{LO}	Output Leakage	GND ≤ V _{OUT} ≤ V _{CC} , Outputs Disabled		-1	1	μA

Notes:

1. Undershoot: -1.0V for pulse width less than 10ns. Not 100% tested.
2. Overshoot: V_{DD} + 1.0V for pulse width less than 10ns. Not 100% tested.

IS62WV2568ALL, IS62WV2568BLL

CAPACITANCE⁽¹⁾

Symbol	Parameter	Conditions	Max.	Unit
C _{IN}	Input Capacitance	V _{IN} = 0V	8	pF
C _{OUT}	Input/Output Capacitance	V _{OUT} = 0V	10	pF

Note:

1. Tested initially and after any design or process changes that may affect these parameters.

AC TEST CONDITIONS

Parameter	62WV2568ALL (Unit)	62WV2568BLL (Unit)
Input Pulse Level	0.4V to V _{CC} -0.2V	0.4V to V _{CC} -0.3V
Input Rise and Fall Times	5 ns	5ns
Input and Output Timing and Reference Level	V _{REF}	V _{REF}
Output Load	See Figures 1 and 2	See Figures 1 and 2

	1.65-2.2V	2.5V - 3.6V
R1(Ω)	3070	3070
R2(Ω)	3150	3150
V _{REF}	0.9V	1.5V
V _{TM}	1.8V	2.8V

AC TEST LOADS

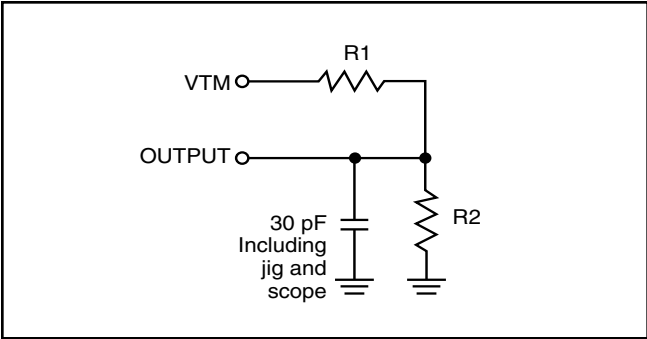


Figure 1

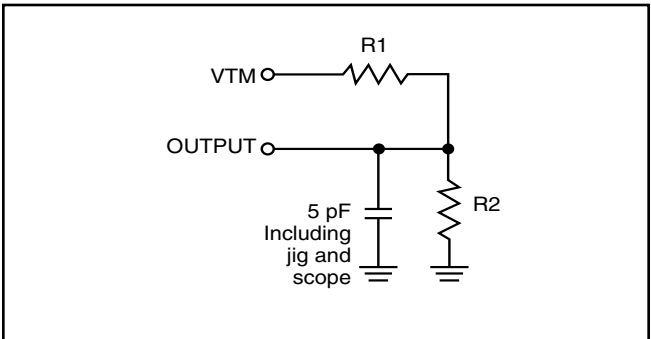


Figure 2

POWER SUPPLY CHARACTERISTICS⁽¹⁾ (Over Operating Range)**62WV2568ALL** (1.65V - 2.2V)

Symbol	Parameter	Test Conditions		Max. 70ns	Unit
I _{CC}	V _{CC} Dynamic Operating Supply Current	V _{CC} = Max., I _{OUT} = 0 mA, f = f _{MAX}	Com. Ind.	15 15	mA
I _{CC1}	Operating Supply Current	V _{CC} = Max., I _{OUT} = 0 mA, f = 0	Com. Ind.	3 3	mA
I _{SB1}	TTL Standby Current (TTL Inputs)	V _{CC} = Max., V _{IN} = V _{IH} or V _{IL} , $\overline{CS1}$ = V _{IH} , CS2 = V _{IL} , f = 1 MHz	Com. Ind.	0.3 0.3	mA
I _{SB2}	CMOS Standby Current (CMOS Inputs)	V _{CC} = Max., $\overline{CS1} \geq V_{CC} - 0.2V$, CS2 $\leq 0.2V$, V _{IN} $\geq V_{CC} - 0.2V$, or V _{IN} $\leq 0.2V$, f = 0	Com. Ind.	5 10	μA

Note:

1. At f = f_{MAX}, address and data inputs are cycling at the maximum frequency, f = 0 means no input lines change.

POWER SUPPLY CHARACTERISTICS⁽¹⁾ (Over Operating Range)**62WV2568BLL** (2.5V - 3.6V)

Symbol	Parameter	Test Conditions		Max. 45ns	Max. 55ns	Max. 70ns	Unit
I _{CC}	V _{CC} Dynamic Operating Supply Current	V _{CC} = Max., I _{OUT} = 0 mA, f = f _{MAX}	Com. Ind.	35 40	30 35	25 30	mA
I _{SB1}	TTL Standby Current (TTL Inputs)	V _{CC} = Max., V _{IN} = V _{IH} or V _{IL} , $\overline{CS1}$ = V _{IH} , CS2 = V _{IL} , f = 1 MHz	Com. Ind.	0.3 0.3	0.3 0.3	0.3 0.3	mA
I _{SB2}	CMOS Standby Current (CMOS Inputs)	V _{CC} = Max., $\overline{CS1} \geq V_{CC} - 0.2V$, CS2 $\leq 0.2V$, V _{IN} $\geq V_{CC} - 0.2V$, or V _{IN} $\leq 0.2V$, f = 0	Com. Ind.	10 10	10 10	10 10	μA

Note:

1. At f = f_{MAX}, address and data inputs are cycling at the maximum frequency, f = 0 means no input lines change.

IS62WV2568ALL, IS62WV2568BLL

READ CYCLE SWITCHING CHARACTERISTICS⁽¹⁾ (Over Operating Range)

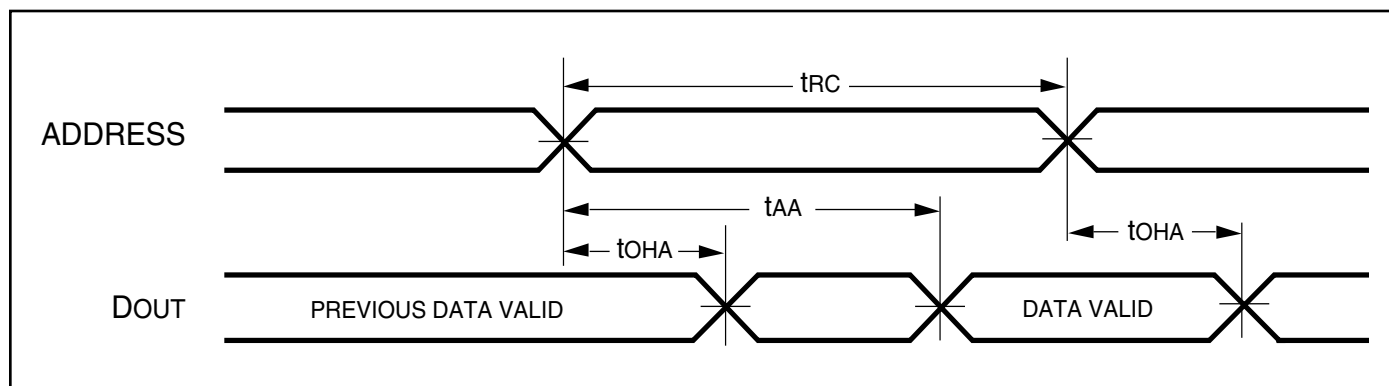
Symbol	Parameter	45ns		55ns		70ns		Unit
		Min.	Max.	Min.	Max.	Min.	Max.	
t _{RC}	Read Cycle Time	45	—	55	—	70	—	ns
t _{AA}	Address Access Time	—	45	—	55	—	70	ns
t _{OHA}	Output Hold Time	10	—	10	—	10	—	ns
t _{ACS1} /t _{ACS2}	$\overline{CS1}$ /CS2 Access Time	—	45	—	55	—	70	ns
t _{DOE}	\overline{OE} Access Time	—	20	—	25	—	35	ns
t _{HZOE} ⁽²⁾	\overline{OE} to High-Z Output	—	15	—	20	—	25	ns
t _{LZOE} ⁽²⁾	\overline{OE} to Low-Z Output	5	—	5	—	5	—	ns
t _{HZCS1} /t _{HZCS2} ⁽²⁾	$\overline{CS1}$ /CS2 to High-Z Output	0	15	0	20	0	25	ns
t _{LZCS1} /t _{LZCS2} ⁽²⁾	$\overline{CS1}$ /CS2 to Low-Z Output	10	—	10	—	10	—	ns

Notes:

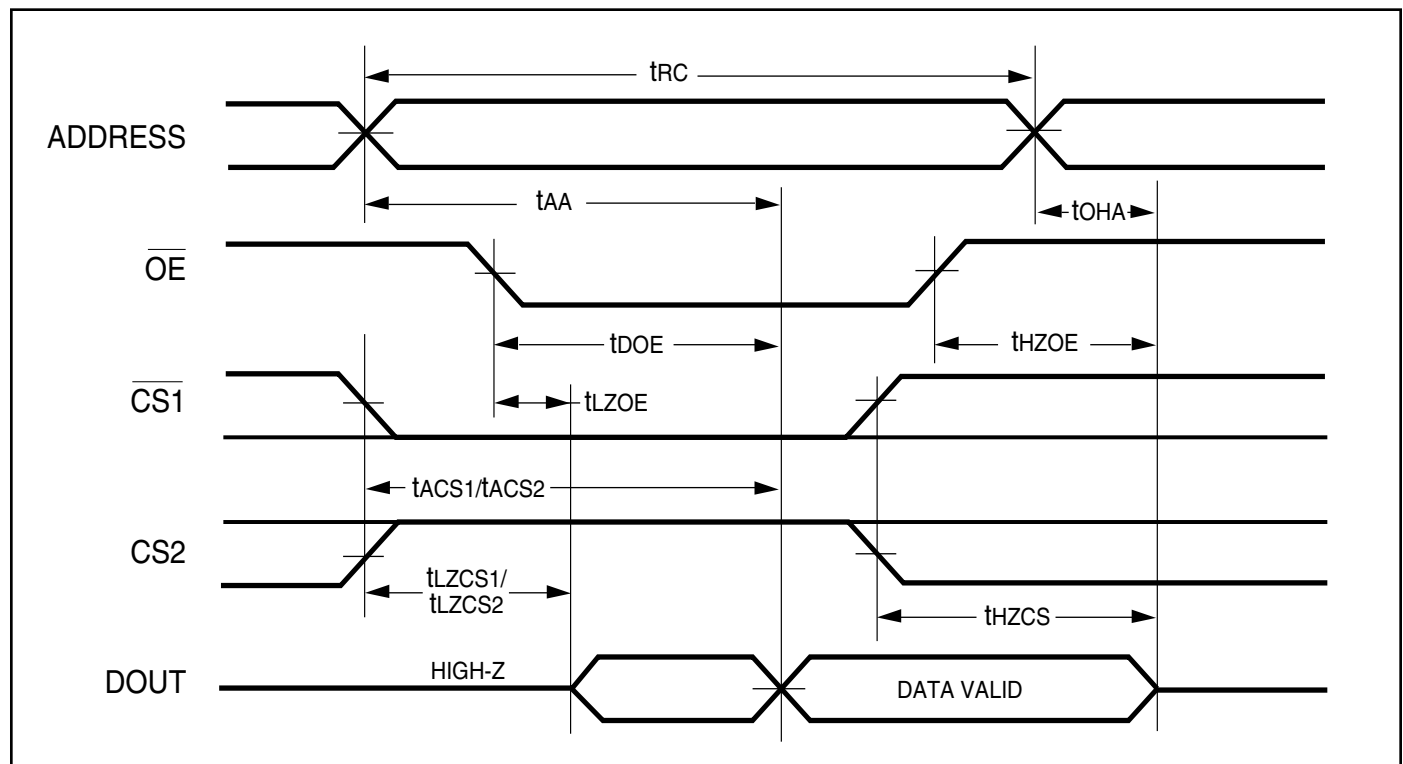
- Test conditions assume signal transition times of 5 ns or less, timing reference levels of 0.9V, input pulse levels of 0.4 to 1.4V and output loading specified in Figure 1.
- Tested with the load in Figure 2. Transition is measured ± 500 mV from steady-state voltage. Not 100% tested.

AC WAVEFORMS

READ CYCLE NO. 1^(1,2) (Address Controlled) ($\overline{CS1} = \overline{OE} = V_{IL}$, CS2 = $\overline{WE} = V_{IH}$)



AC WAVEFORMS

READ CYCLE NO. 2^(1,3) ($\overline{CS1}$, CS2, \overline{OE} Controlled)

Notes:

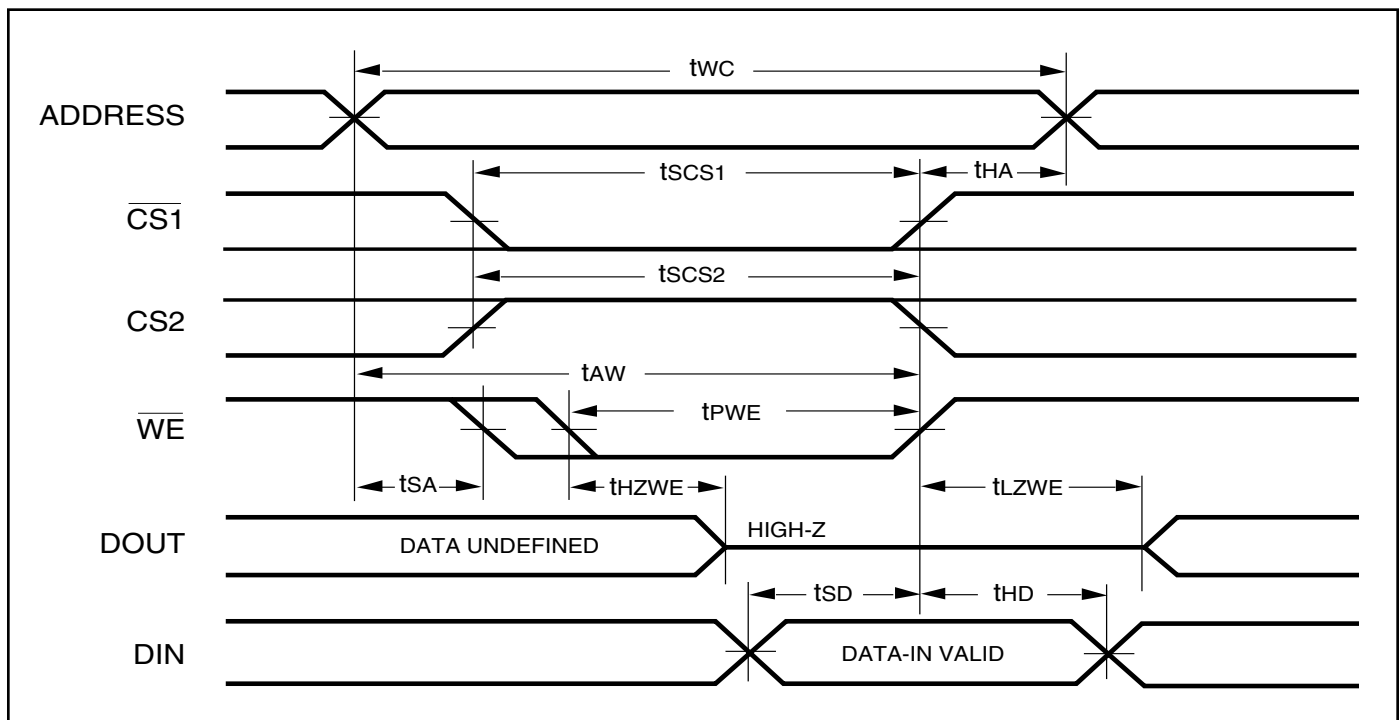
1. \overline{WE} is HIGH for a Read Cycle.
2. The device is continuously selected. \overline{OE} , $\overline{CS1} = V_{IL}$. $CS2 = \overline{WE} = V_{IH}$.
3. Address is valid prior to or coincident with $\overline{CS1}$ LOW and CS2 HIGH transition.

WRITE CYCLE SWITCHING CHARACTERISTICS^(1,2) (Over Operating Range)

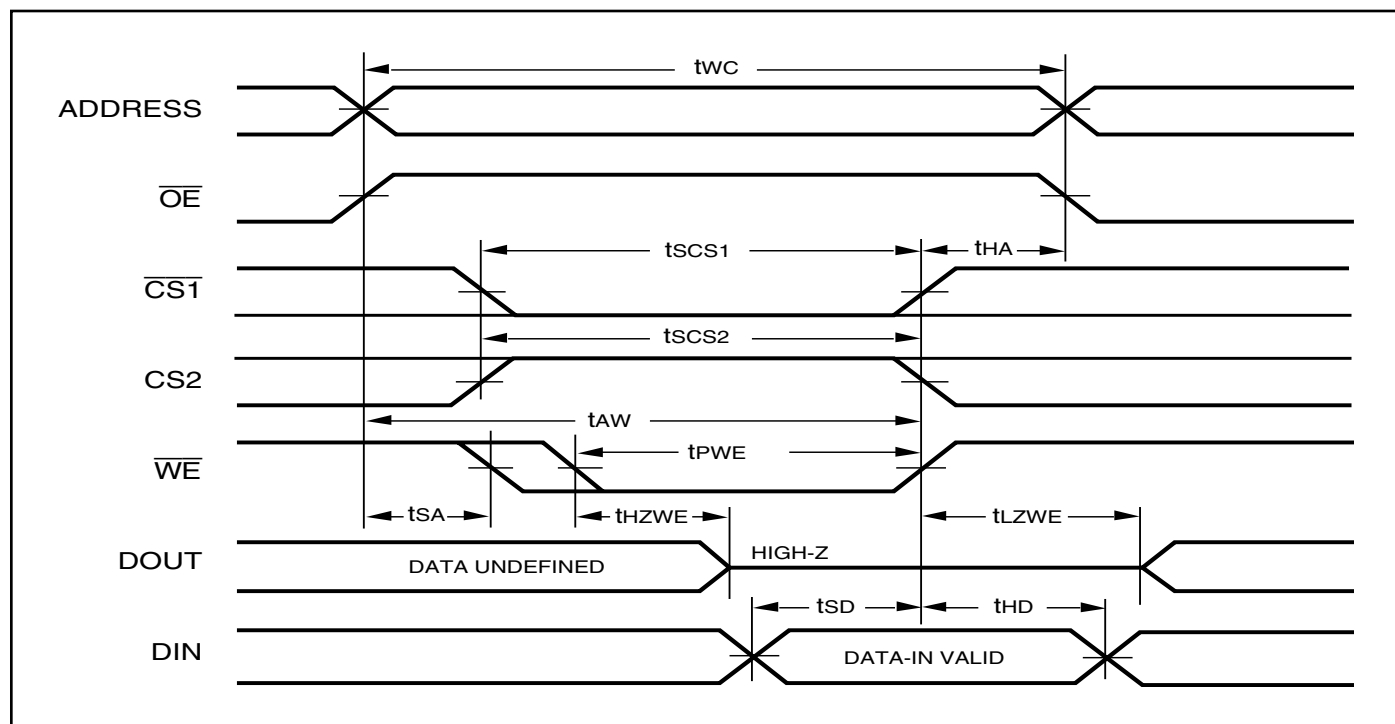
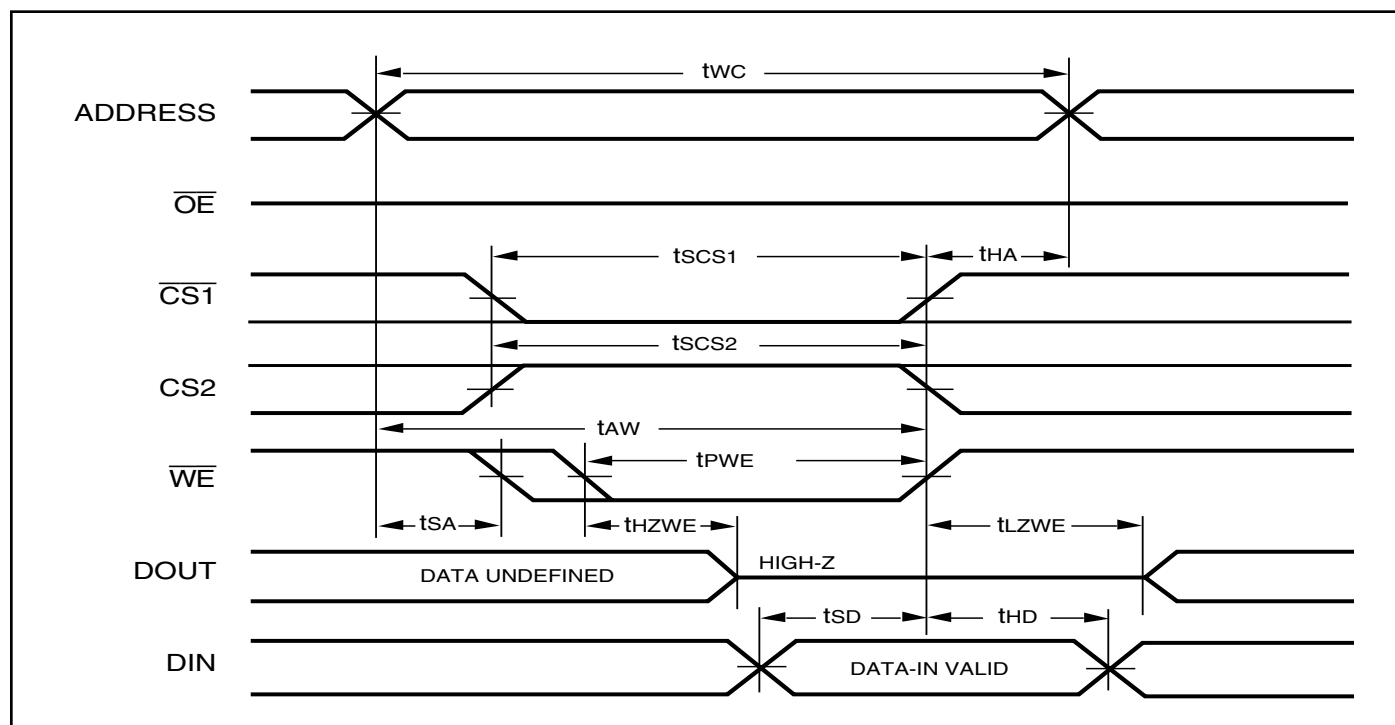
Symbol	Parameter	45ns		55ns		70ns		Unit
		Min.	Max.	Min.	Max.	Min.	Max.	
t _{WC}	Write Cycle Time	45	—	55	—	70	—	ns
t _{SCS1} /t _{SCS2}	$\overline{CS1}$ /CS2 to Write End	35	—	45	—	60	—	ns
t _{AW}	Address Setup Time to Write End	35	—	45	—	60	—	ns
t _{HA}	Address Hold from Write End	0	—	0	—	0	—	ns
t _{SA}	Address Setup Time	0	—	0	—	0	—	ns
t _{PWE}	\overline{WE} Pulse Width	35	—	40	—	50	—	ns
t _{SD}	Data Setup to Write End	20	—	25	—	30	—	ns
t _{HD}	Data Hold from Write End	0	—	0	—	0	—	ns
t _{HZWE}	\overline{WE} LOW to High-Z Output	—	20	—	20	—	20	ns
t _{LZWE}	\overline{WE} HIGH to Low-Z Output	5	—	5	—	5	—	ns

Notes:

1. Test conditions assume signal transition times of 5 ns or less, timing reference levels of 0.9V, input pulse levels of 0.4V to 1.4V and output loading specified in Figure 1.
2. The internal write time is defined by the overlap of $\overline{CS1}$ LOW, CS2 HIGH and \overline{WE} LOW. All signals must be in valid states to initiate a Write, but any one can go inactive to terminate the Write. The Data Input Setup and Hold timing are referenced to the rising or falling edge of the signal that terminates the write.
3. Tested with the load in Figure 2. Transition is measured ± 500 mV from steady-state voltage. Not 100% tested.

AC WAVEFORMS**WRITE CYCLE NO. 1** ($\overline{CS1}$ /CS2 Controlled, \overline{OE} = HIGH or LOW)

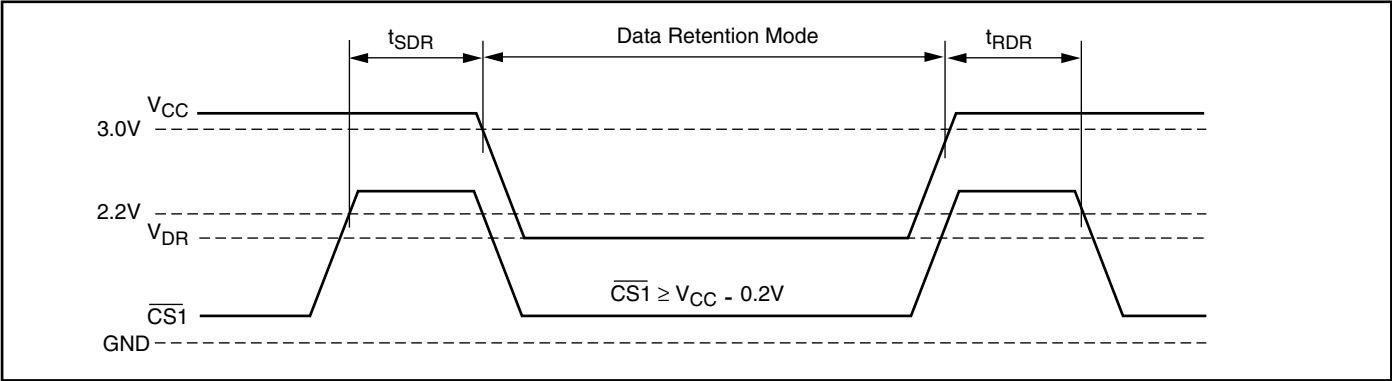
AC WAVEFORMS

WRITE CYCLE NO. 2 (\overline{WE} Controlled: \overline{OE} is HIGH During Write Cycle)WRITE CYCLE NO. 3 (\overline{WE} Controlled: \overline{OE} is LOW During Write Cycle)

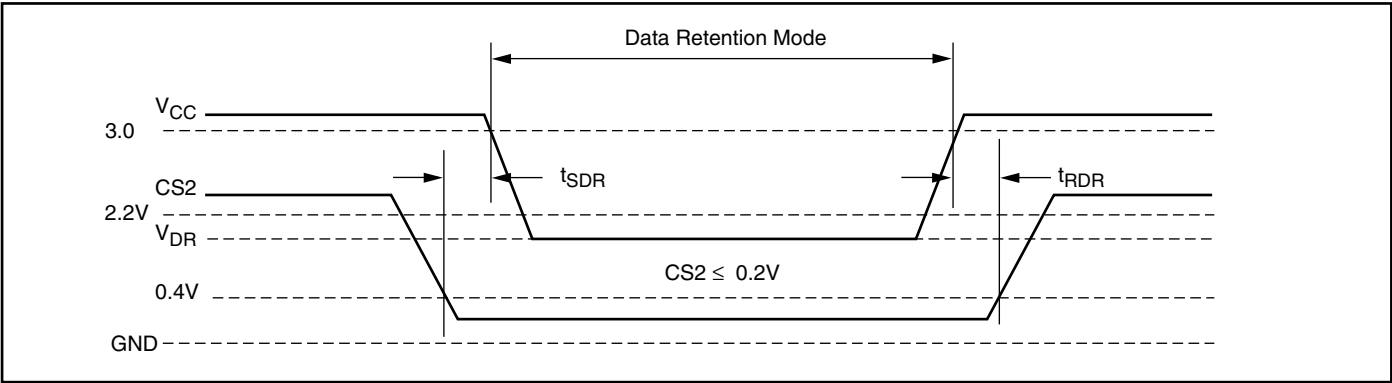
DATA RETENTION SWITCHING CHARACTERISTICS

Symbol	Parameter	Test Condition	Min.	Max.	Unit
V _{DR}	V _{cc} for Data Retention	See Data Retention Waveform	1.0	3.6	V
I _{DR}	Data Retention Current	V _{cc} = 1.0V, $\overline{CS1} \geq V_{cc} - 0.2V$	—	10	μA
t _{SDR}	Data Retention Setup Time	See Data Retention Waveform	0	—	ns
t _{RDR}	Recovery Time	See Data Retention Waveform	t _{rc}	—	ns

DATA RETENTION WAVEFORM ($\overline{CS1}$ Controlled)



DATA RETENTION WAVEFORM (CS2 Controlled)



ORDERING INFORMATION

IS62WV2568ALL (1.65V - 2.2V)

Industrial Range: -40°C to +85°C

Speed (ns)	Order Part No.	Package
70	IS62WV2568ALL-70TLI	TSOP, TYPE I, Lead-free
70	IS62WV2568ALL-70BI	mini BGA (6mm x 8mm)
70	IS62WV2568ALL-70BLI	mini BGA (6mm x 8mm), Lead-free
70	IS62WV2568ALL-70HLI	sTSOP, TYPE I, Lead-free

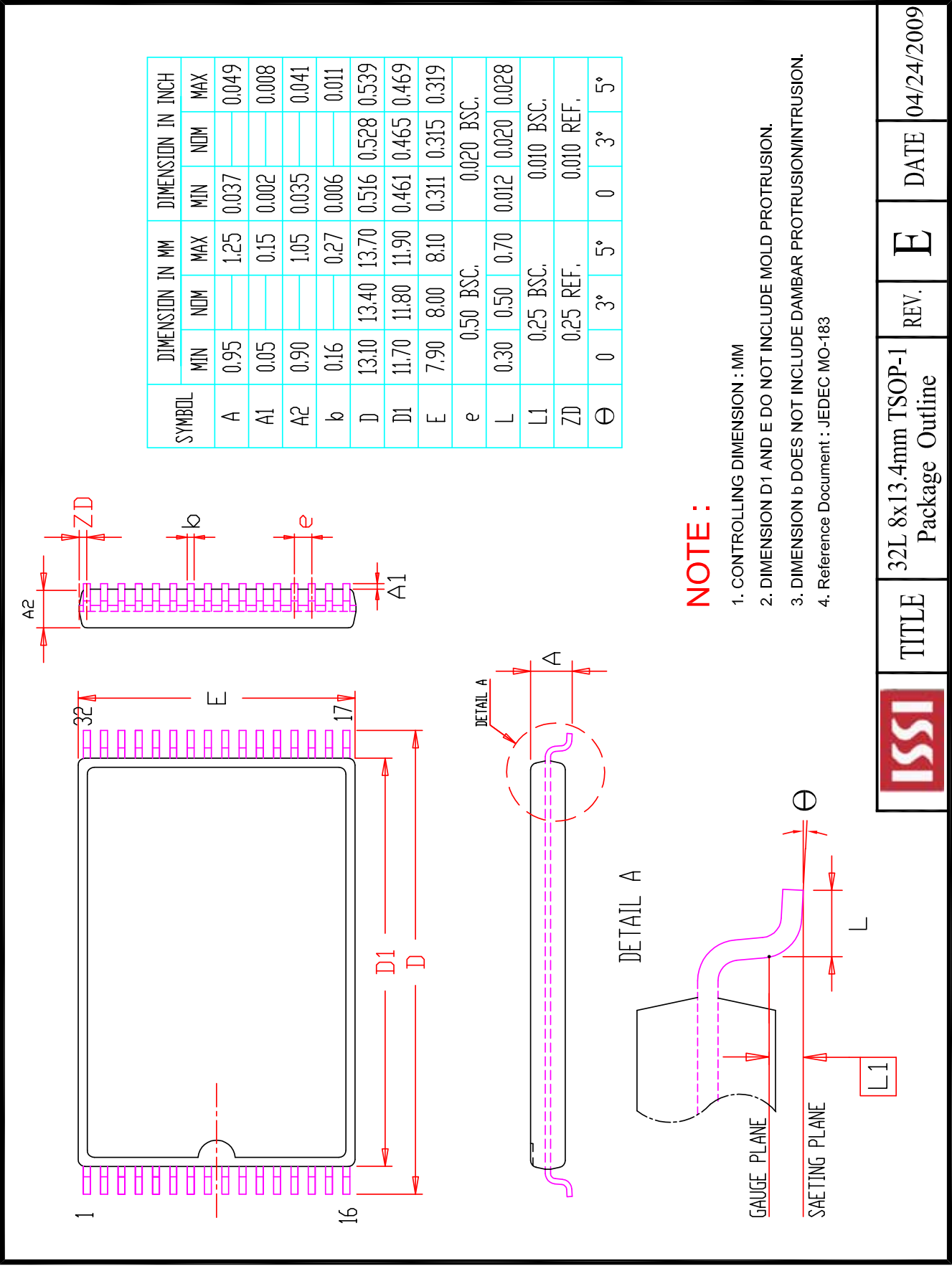
IS62WV2568BLL (2.5V - 3.6V)

Commercial Range: 0°C to +70°C

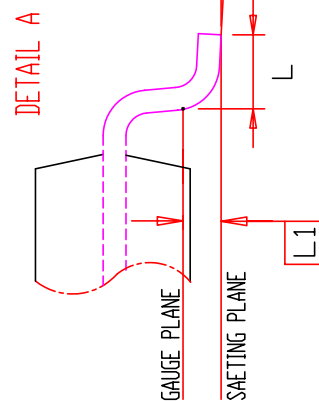
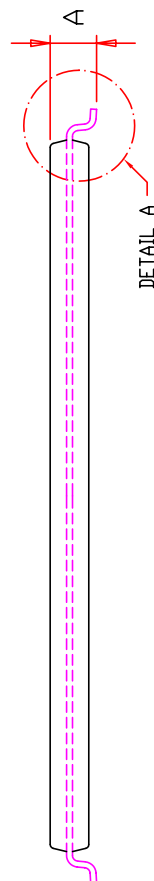
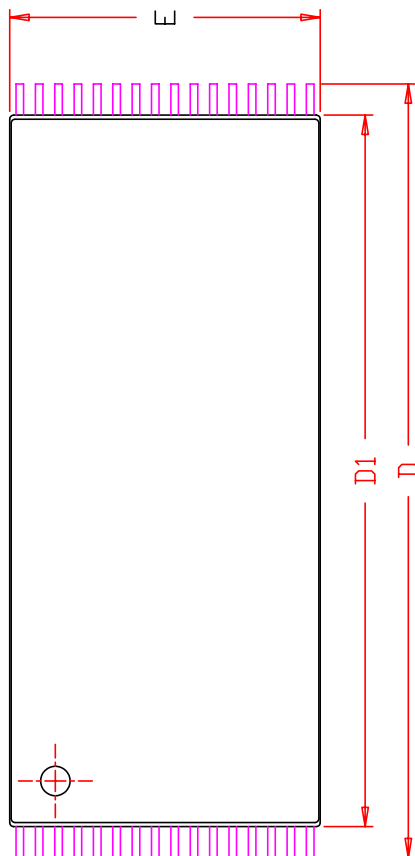
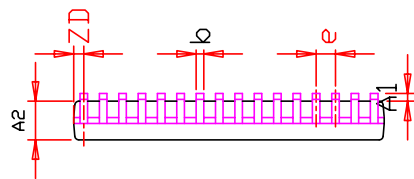
Speed (ns)	Order Part No.	Package
70	IS62WV2568BLL-70B	mini BGA (6mm x 8mm)

Industrial Range: -40°C to +85°C

Speed (ns)	Order Part No.	Package
45	IS62WV2568BLL-45TLI	TSOP, TYPE I, Lead-free
45	IS62WV2568BLL-45BLI	mini BGA (6mm x 8mm), Lead-free
45	IS62WV2568BLL-45HLI	sTSOP, TYPE I
55	IS62WV2568BLL-55TLI	TSOP, TYPE I, Lead-free
55	IS62WV2568BLL-55BI	mini BGA (6mm x 8mm)
55	IS62WV2568BLL-55BLI	mini BGA (6mm x 8mm), Lead-free
55	IS62WV2568BLL-55HLI	sTSOP, TYPE I, Lead-free
70	IS62WV2568BLL-70BI	mini BGA (6mm x 8mm)



	TITLE	32L 8x13.4mm TSOP-1 Package Outline	REV.	E	DATE	04/24/2009
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NOTE ::

1. Controlling dimension : mm
2. Dimension D1 adn E do not include mold protrusion .
3. Dimension b does not include dambar protrusion/intrusion.
4. Formed leads shall be planar with respect to one another within 0.1mm at the seating plane after final test.

SYMBOL	DIMENSION IN MM		
	MIN	NOM	MAX
A	1.00		1.20
A1	0.05		0.20
A2	0.95	1.00	1.05
b	0.17		0.27
D	19.80	20.00	20.20
D1	18.30	18.40	18.50
E	7.80	8.00	8.20
e	0.50 BSC.		
L	0.40		0.70
L1	0.25 BSC.		
ZD	0.25 REF.		
Θ	0	5°	8°

	TITLE	32L 8x20mm TSOP-1 Package Outline	REV.	E	DATE	06/08/2006
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